捷**SN54AS82BA样SN74AS82BA出SN**74AS824A 9-BIT BUS-INTERFACE FLIP-FLOPS WITH 3-STATE OUTPUTS

SDAS231A - JUNE 1984 - REVISED AUGUST 1995

- Functionally Equivalent to AMD's AM29823 and AM29824
- Provide Extra Data Width Necessary for Wider Address/Data Paths or Buses With **Parity**
- Outputs Have Undershoot-Protection Circuitry
- Power-Up High-Impedance State
- Buffered Control Inputs to Reduce dc Loading Effects
- Package Options Include Plastic Small-Outline (DW) Packages, Ceramic Chip Carriers (FK), and Standard Plastic (NT) and Ceramic (JT) 300-mil DIPs

description

These 9-bit flip-flops feature 3-state outputs designed specifically for driving highly capacitive or relatively low-impedance loads. These devices are particularly suitable for implementing wider buffer registers, I/O ports, bidirectional bus drivers, parity bus interfacing, and working registers.

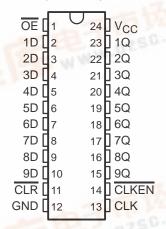
With the clock-enable (CLKEN) input low, the nine D-type edge-triggered flip-flops enter data on the low-to-high transitions of the clock (CLK) input. Taking CLKEN high disables the clock buffer, latching the outputs. The SN54AS823A and SN74AS823A have noninverting data (D) inputs and the SN74AS824A has inverting (D) inputs. Taking the clear (CLR) input low causes the nine Q outputs to go low independently of the clock.

A buffered output-enable (OE) input can be used to place the nine outputs in either a normal logic state (high or low logic level) or the highimpedance state. In the high-impedance state, the outputs neither load nor drive the bus lines significantly. The high-impedance state and increased drive provide the capability to drive bus lines without interface or pullup components.

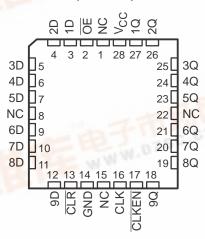
OE does not affect the internal operation of the flip-flops. Old data can be retained or new data can be entered while the outputs are in the high-impedance state.

The SN54AS823A is characterized for operation over the full military temperature range of -55°C to 125°C. The SN74AS823A and SN74AS824A are characterized for operation from 0°C to 70°C.

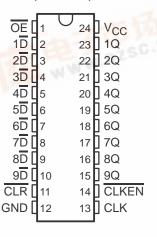
SN54AS823A . . . JT PACKAGE SN74AS823A . . . DW OR NT PACKAGE (TOP VIEW)



SN54AS823A . . . FK PACKAGE (TOP VIEW)



SN74AS824A . . . DW OR NT PACKAGE (TOP VIEW)



NC - No internal connection

SDAS231A - JUNE 1984 - REVISED AUGUST 1995

Function Tables

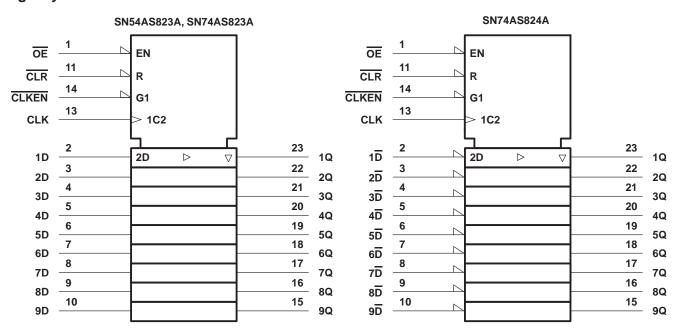
SN54AS823A, SN74AS823A (each flip-flop)

	INPUTS					
OE	CLR	CLKEN	CLK	D	Q	
L	L	Х	Х	Х	L	
L	Н	L	\uparrow	Н	Н	
L	Н	L	\uparrow	L	L	
L	Н	Н	Χ	Χ	Q_0	
Н	Χ	Χ	Χ	Χ	Z	

SN74AS824A (each flip-flop)

		INPUTS		OUTPUT	
OE	CLR	CLKEN	CLK	D	Q
L	L	Х	Χ	Х	L
L	Н	L	\uparrow	Н	L
L	Н	L	\uparrow	L	Н
L	Н	Н	Χ	X	Q ₀
Н	Χ	X	Χ	Χ	Z

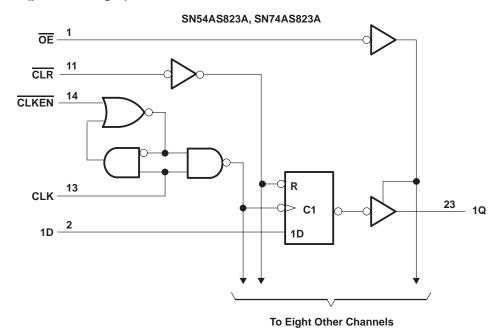
logic symbols†

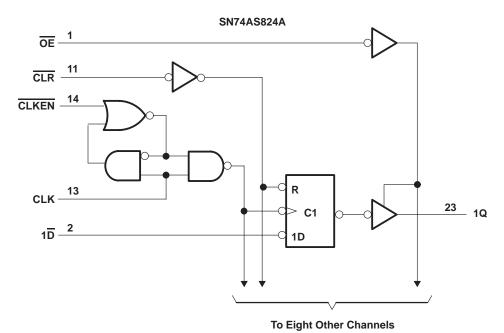


[†] These symbols are in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12. Pin numbers shown are for the DW, JT, and NT packages.



logic diagrams (positive logic)





Pin numbers shown are for the DW, JT, and NT packages.

SN54AS823A, SN74AS823A, SN74AS824A 9-BIT BUS-INTERFACE FLIP-FLOPS WITH 3-STATE OUTPUTS

SDAS231A - JUNE 1984 - REVISED AUGUST 1995

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage, V _{CC}	
Input voltage, V _I	7 V
Voltage applied to a disabled 3-state output	
Operating free-air temperature range, T _A : SN54AS823A	−55°C to 125°C
SN74AS823A, SN74AS824A	0°C to 70°C
Storage temperature range	-65°C to 150°C

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

recommended operating conditions

			SN	SN54AS823A		SN74AS823A SN74AS824A			UNIT
			MIN	NOM	MAX	MIN	NOM	MAX	
VCC	Supply voltage		4.5	5	5.5	4.5	5	5.5	V
VIH	High-level input voltage		2			2			V
VIL	Low-level input voltage		T		0.8			0.8	V
IOH	High-level output current		T		-24			-24	mA
l _{OL}	Low-level output current				32			48	mA
+ *	Pulse duration	CLR low	7.5			6.5			ns
t _W *	Fulse duration	CLK high or low	9.5			8			
		CLR high	8			8			
t _{su} *	Setup time before CLK↑	Data	7			6			ns
		CLKEN high or low	8.5			7.5			
th*	Hold time after CLK↑	CLKEN low	0			0			ns
TA	Operating free-air temperature	·	-55		125	0		70	°C

^{*} On products compliant to MIL-STD-883, Class B, this parameter is based on characterization data but is not production tested.



SN54AS823A, SN74AS823A, SN74AS824A 9-BIT BUS-INTERFACE FLIP-FLOPS WITH 3-STATE OUTPUTS

SDAS231A - JUNE 1984 - REVISED AUGUST 1995

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS		SN	SN54AS823A			SN74AS823A SN74AS824A			
				MIN	TYP [†]	MAX	MIN	TYP [†]	MAX		
٧ıĸ		$V_{CC} = 4.5 \text{ V},$	I _I = -18 mA			-1.2			-1.2	V	
		$V_{CC} = 4.5 \text{ V to } 5.5 \text{ V},$	I _{OH} = −2 mA	V _{CC} -2	2		V _{CC} -2	<u>)</u>			
Vон		V 45V	I _{OH} = -15 mA	2.4	3.2		2.4	3.2		V	
		V _{CC} = 4.5 V	$I_{OH} = -24 \text{ mA}$	2			2				
V		V 45V	I _{OL} = 32 mA		0.3	0.5				V	
VOL		V _{CC} = 4.5 V	I _{OL} = 48 mA					0.35	0.5	V	
lozh		$V_{CC} = 5.5 \text{ V},$	V _O = 2.7 V			50			50	μΑ	
lozL		$V_{CC} = 5.5 \text{ V},$	V _I = 0.4 V			-50			-50	μΑ	
lį		$V_{CC} = 5.5 \text{ V},$	V _I = 7 V			0.1			0.1	mA	
l _{IH}		V _{CC} = 5.5 V,	V _I = 2.7 V			20			20	μΑ	
Ι _{ΙL}		V _{CC} = 5.5 V,	V _I = 0.4 V			-0.5			-0.5	mA	
1 ₀ ‡		V _{CC} = 5.5 V,	V _O = 2.25 V	-30		-112	-30		-112	mA	
			Outputs high		49	80		49	80		
	SN54AS823A, SN74AS823A	V _{CC} = 5.5 V	Outputs low		61	100		61	100		
	31174730237		Outputs disabled		64	103		64	103	mA	
ICC	SN74AS824A		Outputs high		49	80		49	80		
		V _{CC} = 5.5 V	Outputs low		61	100		61	100		
			Outputs disabled		64	103		64	103		

switching characteristics (see Figure 1)

PARAMETER	FROM (INPUT)	то (ОИТРИТ)	V _C C _L R1 R2 T _A	UNIT			
	, ,		SN54AS823A		SN74AS823A SN74AS824A		
			MIN	MAX	MIN	MAX	
^t PLH	CLK	A O	3.5	9	3.5	7.5	ns
^t PHL		Any Q	3.5	14	3.5	13	115
^t PHL	CLR	Any Q	3.5	16.5	3.5	15.5	ns
^t PZH		Any Q	4	12	4	11	ns
t _{PZL}	ŌĒ		4	13	4	12	115
^t PHZ	ŌĒ	Any Q	1	10	1	8	ns
^t PLZ	OE .	Ally Q	1	10	1.5	8	115

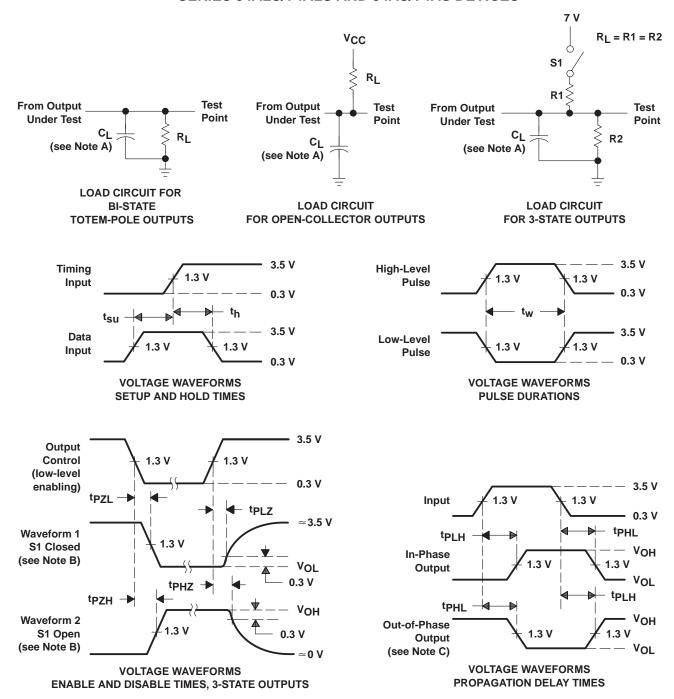
[§] For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.



[†] All typical values are at V_{CC} = 5 V, T_A = 25°C. ‡ The output conditions have been chosen to produce a current that closely approximates one half of the true short-circuit output current, I_{OS}.

SDAS231A - JUNE 1984 - REVISED AUGUST 1995

PARAMETER MEASUREMENT INFORMATION SERIES 54ALS/74ALS AND 54AS/74AS DEVICES



NOTES: A. C_L includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. When measuring propagation delay items of 3-state outputs, switch S1 is open.
- D. All input pulses have the following characteristics: PRR \leq 1 MHz, $t_r = t_f = 2$ ns, duty cycle = 50%.
- E. The outputs are measured one at a time with one transition per measurement.

Figure 1. Load Circuits and Voltage Waveforms



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